

SUBSTITUTE FORM PTO-1449A LIST OF PATENTS AND APPLICANT'S INFORMATION DISCLOSURE STATEMENT		Atty Docket: Serial No.: Applicant: Filing Date: Group:	02AG49153548 Not Yet Assigned ALBERICI Herewith	10574868 - GAU: 4183
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U.S. PATENT DOCUMENTS

Examiner Initials	Document Number	Date	Name	Class	Sub Class	Filing Date
AA	6,104,029	8/15/00	Coxon et al.	250	305	
AB	2001/0052744	12/20/01	Tsuno	313	364	
AC						
AD						
AE						
AF						
AG						
AH						
AI						

FOREIGN PATENT DOCUMENTS

	Document Number	Date	Country	Class	Sub Class	Translation
AJ						
AK						
AL						

OTHER ART (Including Author, Title, Date, Pertinent Pages, etc.)

AM	Hayashi et al., Energy Loss Near-Edge Structure for Materials Containing Light Elements by Reflection Electron Energy Loss Spectroscopy, Applied Physics Letters, American Institute of Physics, New York, Vol. 66, No. 1, January 2, 1995, Pages 25-27
AN	Ertl et al., Low Energy Electrons and Surface Chemistry, 1985, VCH Verlagsgesellschaft MBH, Weinheim, Germany, Pages 6-25, 185-200, 285-291
AO	Mook et al., Electrostatic In-Line Monochromator for Schottky Field Emission Gun, Institute of Physics Conference Series, IOP Publishing, No. 153, 1997, Pages 81-84
AP	Browning et al., A Digital Scanning Auger Electron Microscope Incorporation a Concentric Hemispherical Analyser, Proceedings of the Royal Society of London, Series A, Mathematical and Physical Sciences, Royal Society of London, Vol. 357, No. 1689, 1977, Pages 213-230
AQ	Henrard et al., Electron-Energy-Loss Spectroscopy of Plasmon Excitations in Concentric-Shell Fullerenes, Physical Review B (Condensed Matter) APS Through AIP USA, Vol. 59, No. 8, February 15, 1999, Pages 5832-5836
AR	

EXAMINER:	/Hanway Chang/	DATE CONSIDERED:	02/17/2009
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***EXAMINER:** Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

ALL REFERENCES CONSIDERED EXCEPT WHERE LINED THROUGH. /H.C./